Appl. No. 10/637,224 Amdt. Dated November 30, 2004

Reply to Office Action of August 31, 2004

Amendments to the Specification

On page 4, in the "Brief Description of the Drawings" section, following the description of Fig. 9 (following line 17), add the following new paragraph:

Fig. 10 is a flow diagram illustrating a method for examining a signal supply apparatus according to the present invention.

Replace the paragraph beginning at page 5, line 30, and ending at page 6, line 5, with the following amended paragraph:

In an examination mode 200 in accordance with the present embodiment, and with reference to the flow diagram of Fig. 10, the output lines 16-1 through 16-3 of the respective three voltage followers 14-1 through 14-3 are short-circuited (step 202). Then, in step 204, a current value of the closed circuit thus short-circuited is measured through the output examination terminals 32 and 34. For example, the current value is measured as I₁. In this instance, when the measured composite current value I₁ is less than a reference current value I_{ref1} (steps 206, 208), the apparatus is determined to be a good product (step 210). Conversely, when the composite current value I₁ exceeds the reference current value I_{ref1}, the apparatus is determined to be a bad product (step 212).